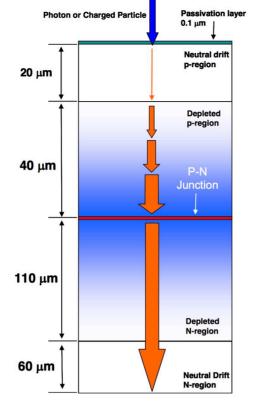
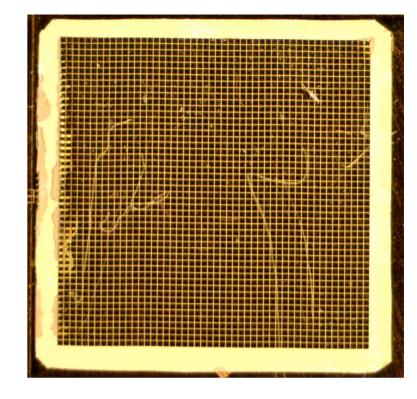
- Deep depleted APD read out through capacitatively coupled mesh
 - Silicon is biased, image charge read out
 - Gain layer and drift region overlap
 - Mesh serves to stabilize E-field shape over large area for good performance over whole device
 - Operates at high gain / high voltage
- 20 ps resolution achieved on 8x8mm2 nonirradiated device





No conclusive results yet for irradiated devices

